

Search Notes

Application/Control No.

10/826,571

Examiner

John D. Lee

Applicant(s)/Patent under
Reexamination

FUJIWARA ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
359	325,326	9/14/2005	JDL
359	276,278	9/14/2005	JDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	9/14/2005	JDL
IEEE Xplore Database searched; search strategy on separate sheet.	9/14/2005	JDL